

PTO/SB/08a/b (07-05)

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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)			Complete if Known		
			Application Number	10/758710-Conf. #6546	
			Filing Date	January 16, 2004	
			First Named Inventor	Martin W. Rupich	
			Art Unit	1762	
			Examiner Name	Not Yet Assigned	
Sheet	1	of	3	Attorney Docket Number	0002802.00174US1

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
	AA*	US-2002/0056401-A1	05-16-2002	Rupich et al.	
	AB	US-2002/178999-A1	12-05-2002	Beach et al.	
	AC*	US-2005/0065035-A1	03-24-2005	Rupich et al.	
	AD*	US-5,231,074	07-27-1993	Cima et al.	
	AE*	US-5,627,140-A	05-06-1997	Fossheim et al.	
	AF*	US-5,683,967	11-04-1997	Frenkel	
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		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)			
	BA	WO-00/058530	10-05-2000	American Superconductor Corporation	
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	BC	WO-01/08169	02-01-2001	American Superconductor Corporation	
	BD	WO-01/08170	02-01-2001	American Superconductor Corporation	
Examiner Signature				Date Considered	1/11/08

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BE	WO-01/08231	02-01-2001	American Superconductor Corporation		
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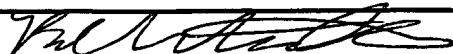
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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
MJ	CA	Ashworth, et al., "AC Losses in Silver Clad Tc Superconducting Tapes," Chinese Journal of Physics, 1996, Vol. 34(2-11), pp. 232-242.	
	CB	Babu, et al., "New Chemically Stable, Nano-Size Artificial Flux Pinning Centres in (RE)-Ba-Cu-O Superconductors," Superconductor Sci. and Tech., 2003, Vol. 16, L44-L45.	
	CC	Beach, et al., "Sol-Gel Synthesis of Rare Earth Aluminate Films as Buffer Layers for High T _c Superconducting Films," Mat. Res. Soc. Symp. Proc., 1998, Vol. 495, pp. 263-270.	
	CD	Carr, et al., "Filamentary YBCO Conductors for AC Applications," I.E.E.E. Transactions on Applied Superconductivity, 1999, Vol. 9(2), pp. 1475-1478.	
	CE	Chevtchenko et al., "Proposal to Convert a Second-Generation High Temperature Superconducting DC tape into an AC Tape," 6 pp.	
	CF	di Uccio et al., "Phase Competition Between Y ₂ BaCuO ₅ and Y ₂ O ₃ Precipitates in Y-rich YBCO Thin Films," Physica C, 1999, Vol. 321, pp. 162-176.	
Examiner Signature	Paul W. [Signature]		Date Considered 1/11/08

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CG	Gammel et al., "Observation of Hexagonally Correlated Flux Quanta in YBa ₂ Cu ₃ O ₇ , Phys. Rev. Lett., 1987, Vol. 59(22), pp. 2592-2595.
CH	Glowacki, et al., "A New Method for Decreasing Transport AC Losses in Multifilamentary Coated Superconductors," Physica C, 2001, Vol. 357-360, pp. 1213-1217.
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CL	Kehl, "The Principles of Metallographic Laboratory Practice," Third Edition, 1949, McGraw-Hill Book Company.
CM	Lee et al., "Alternative Buffer Architectures for High Critical Current Density YBCO Superconducting Deposits on Rolling Assisted Biaxially-Textured Substrates," Jpn. J. Appl. Phys., 1999, Vol. 38, pp. L178-L180.
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CP	Malozemoff, "Second Generation HTS Wire: An Assessment," 2004, American Superconductor Brochure.
CQ	Morrell et al., "Sol-Gel Synthesis of Epitaxial Films of (Sr, Ba) Bi ₂ (Nb,Ta) ₂ O ₉ and Bi ₄ Ti ₃ O ₁₂ on [100] SrTiO ₃ , Mat. Res. Soc. Symp. Proc., 1998, Vol. 495, pp. 271-276.
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CV	Shoup et al., "Epitaxial Thin Film Growth of Lanthanum and Neodymium Aluminate Films on Roll-Textured Nickel Using a Sol-Gel Method," J. Am. Cer. Soc., 1998, Vol. 81, pp. 3019-3021.
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CX	Wolf, et al., "Silicon Processing for the VLSI Era," 1986, Vol. 1, pp. 539-574, Lattice Press, Sunset Park, CA.
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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